

FEATURES

- ❑ 12 x 12-bit Multiplier with Pipelined 26-bit Output Summer
- ❑ Summer has 26-bit Input Port Fully Independent from Multiplier Inputs
- ❑ Cascadable to Form Video Rate FIR Filter with 3-bit Headroom
- ❑ A, B, and C Input Registers Separately Enabled for Maximum Flexibility
- ❑ 28 MHz Data Rate for FIR Filtering Applications
- ❑ High Speed, Low Power CMOS Technology
- ❑ 84-pin PLCC, J-Lead

DESCRIPTION

The **LMS12** is a high-speed 12 x 12-bit combinatorial multiplier integrated with a 26-bit adder in a single 84-pin package. It is an ideal building block for the implementation of very high-speed FIR filters for video, RADAR, and other similar applications. The LMS12 implements the general form $(A \cdot B) + C$. As a result, it is also useful in implementing polynomial approximations to transcendental functions.

ARCHITECTURE

A block diagram of the LMS12 is shown below. Its major features are discussed individually in the following paragraphs.

MULTIPLIER

The A11-0 and B11-0 inputs to the LMS12 are captured at the rising edge of the clock in the 12-bit A and B input registers, respectively. These registers are independently enabled by the

\overline{ENA} and \overline{ENB} inputs. The registered input data are then applied to a 12 x 12-bit multiplier array, which produces a 24-bit result. Both the inputs and outputs of the multiplier are in two's complement format. The multiplication result forms the input to the 24-bit product register.

SUMMER

The C25-0 inputs to the LMS12 form a 26-bit two's complement number which is captured in the C register at the rising edge of the clock. The C register is enabled by assertion of the \overline{ENC} input. The summer is a 26-bit adder which operates on the C register data and the sign extended contents of the product register to produce a 26-bit sum. This sum is applied to the 26-bit S register.

OUTPUT

The FTS input is the feedthrough control for the S register. When FTS is asserted, the summer result is applied directly to the S output port. When FTS is deasserted, data from the S register is output on the S port, effecting a one-cycle delay of the summer result. The S output port can be forced to a high-impedance state by driving the \overline{OE} control line high. FTS would be asserted for conventional FIR filter applications, however the insertion of zero-coefficient filter taps may be accomplished by negating FTS. Negating FTS also allows application of the same filter transfer function to two interleaved datastreams with successive input and output sample points occurring on alternate clock cycles.

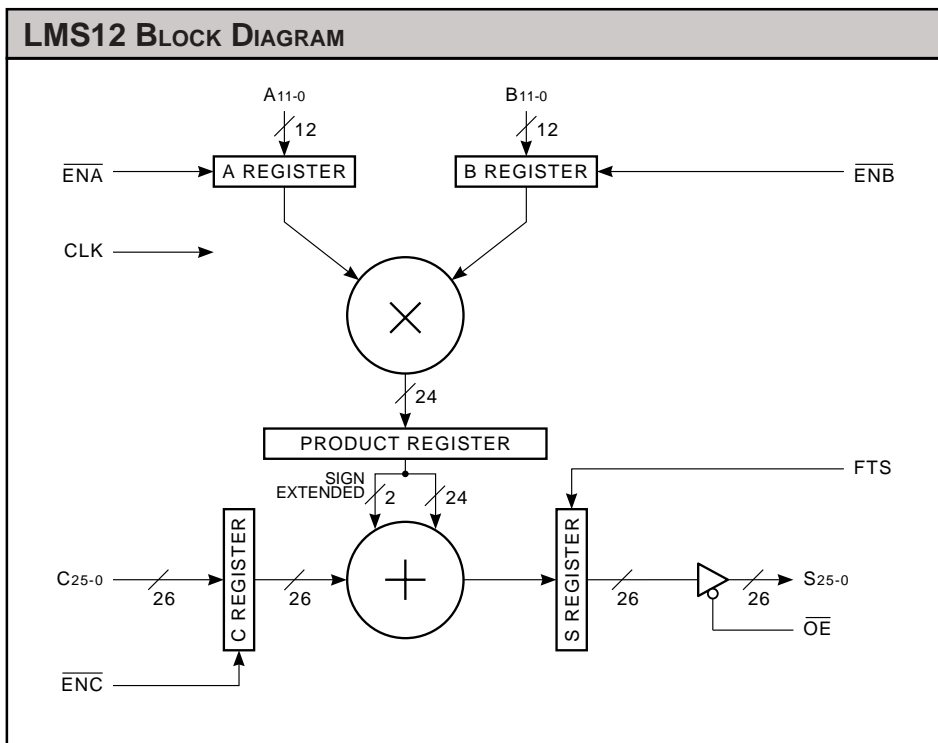
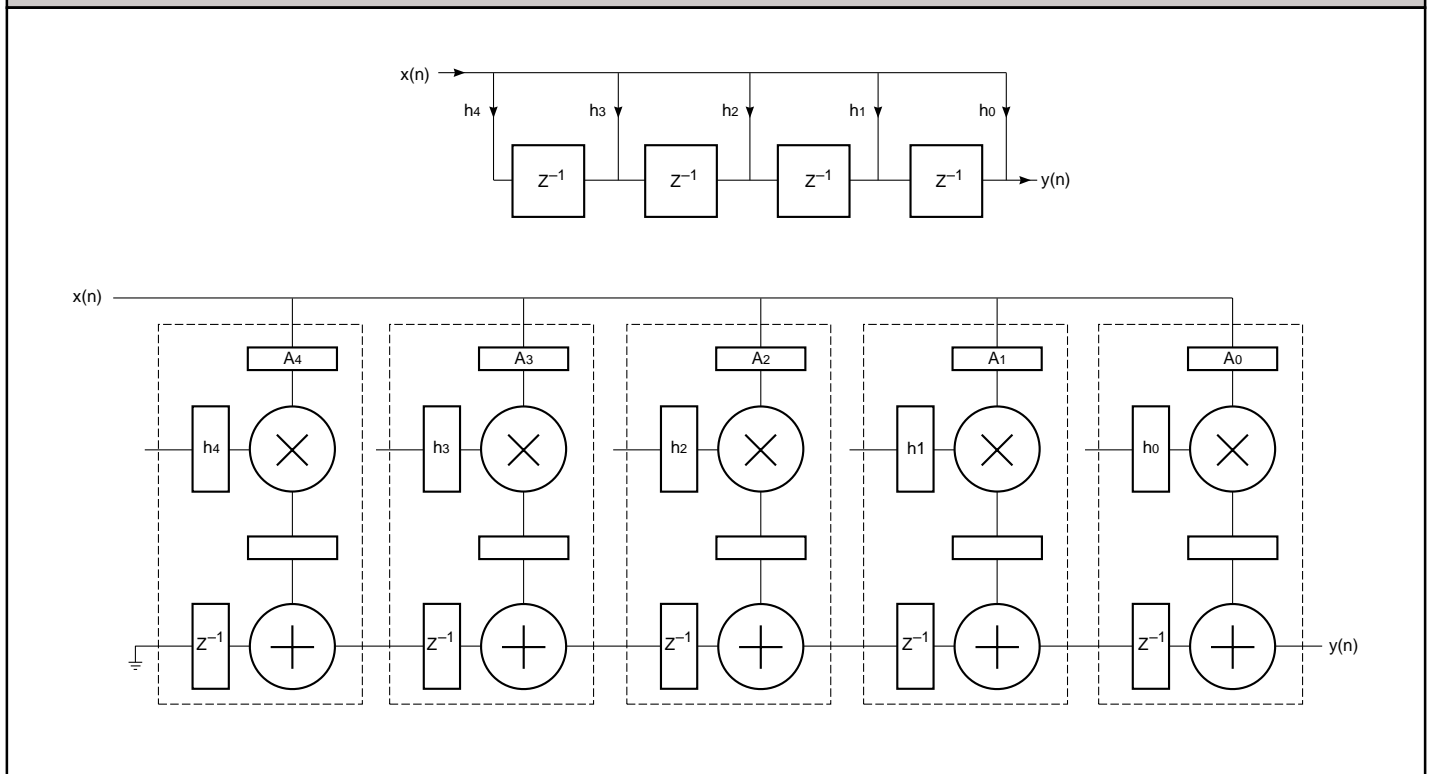


FIGURE 1. FLOW DIAGRAM FOR 5-TAP FIR FILTER



APPLICATIONS

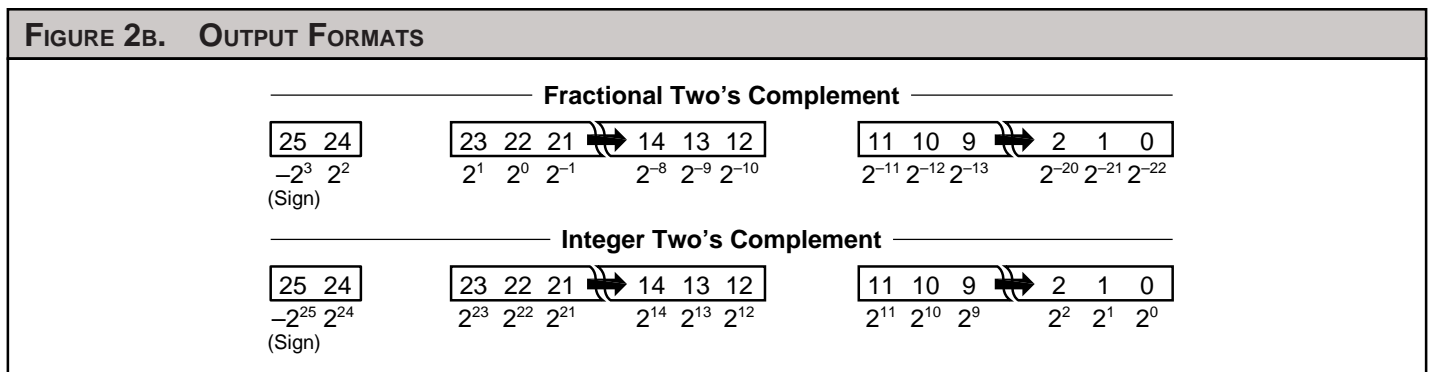
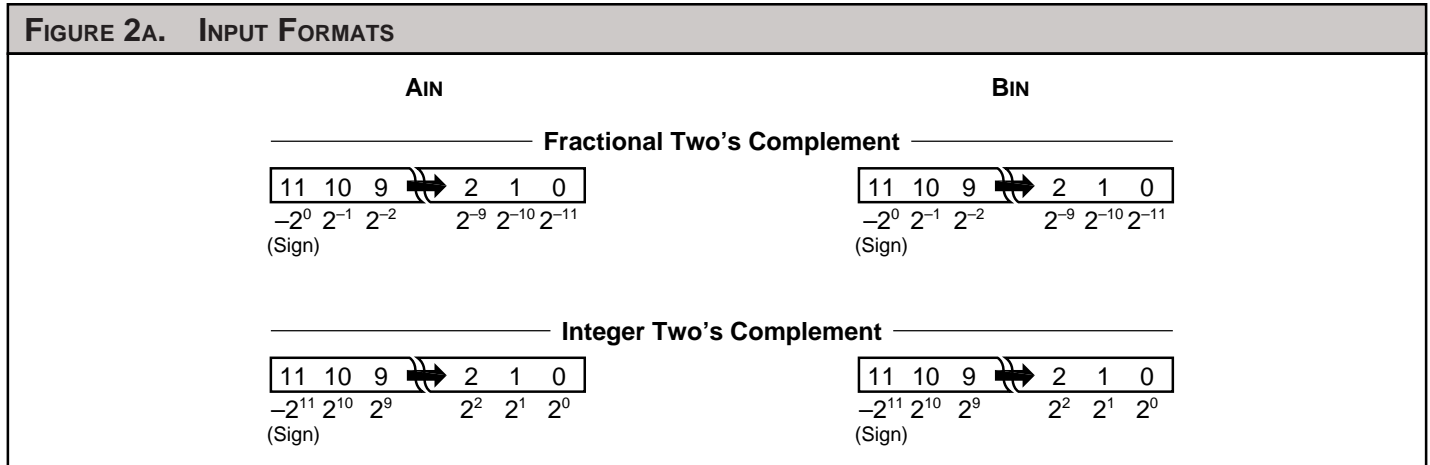
The LMS12 is designed specifically for high-speed FIR filtering applications requiring a throughput rate of one output sample per clock period. By cascading LMS12 units, the transpose form of the FIR transfer function is implemented directly, with each of the LMS12 units supplying one of the filter weights, and the cascaded summers accumulating the results. The signal flow graph for a 5-tap FIR filter and the equivalent implementation using LMS12's is shown in Figure 1.

The operation of the 5-tap FIR filter implementation of Figure 1 is depicted in Table 1. The filter weights $h_4 - h_0$ are assumed to be latched in the B input registers of the LMS12 units. The $x(n)$ data is applied in parallel to the A input registers of all devices. For descriptive purposes in the table, the A register contents and sum output data of each device is labelled

according to the index of the weight applied by that device; i.e., S_0 is produced by the rightmost device, which has h_0 as its filter weight and A_0 as its input register contents. Each column represents one clock cycle, with the data passing a particular point in the system illustrated across each row.

TABLE 1. TIMING EXAMPLE FOR 5-TAP NONDECIMATING FIR FILTER

CLK Cycle	1	2	3	4	5	6	7	8	9
X(n)	X _n	X _{n+1}	X _{n+2}	X _{n+3}	X _{n+4}	X _{n+5}	X _{n+6}	X _{n+7}	X _{n+8}
A4 Register Sum 4		X _n	X _{n+1} h ₄ X _n	X _{n+2} h ₄ X _{n+1}	X _{n+3} h ₄ X _{n+2}	X _{n+4} h ₄ X _{n+3}	X _{n+5} h ₄ X _{n+4}	X _{n+6} h ₄ X _{n+5}	X _{n+7} h ₄ X _{n+6}
A3 Register Sum 3		X _n	X _{n+1} h ₃ X _n + h ₄ X _{n-1}	X _{n+2} h ₃ X _{n+1} + h ₄ X _n	X _{n+3} h ₃ X _{n+2} + h ₄ X _{n+1}	X _{n+4} h ₃ X _{n+3} + h ₄ X _{n+2}	X _{n+5} h ₃ X _{n+4} + h ₄ X _{n+3}	X _{n+6} h ₃ X _{n+5} + h ₄ X _{n+4}	X _{n+7} h ₃ X _{n+6} + h ₄ X _{n+5}
A2 Register Sum 2		X _n	X _{n+1} h ₂ X _n + h ₃ X _{n-1} + h ₄ X _{n-2}	X _{n+2} h ₂ X _{n+1} + h ₃ X _n + h ₄ X _{n-1}	X _{n+3} h ₂ X _{n+2} + h ₃ X _{n+1} + h ₄ X _n	X _{n+4} h ₂ X _{n+3} + h ₃ X _{n+2} + h ₄ X _{n+1}	X _{n+5} h ₂ X _{n+4} + h ₃ X _{n+3} + h ₄ X _{n+2}	X _{n+6} h ₂ X _{n+5} + h ₃ X _{n+4} + h ₄ X _{n+3}	X _{n+7} h ₂ X _{n+6} + h ₃ X _{n+5} + h ₄ X _{n+4}
A1 Register Sum 1		X _n	X _{n+1} h ₁ X _n + h ₂ X _{n-1} + h ₃ X _{n-2} + h ₄ X _{n-3}	X _{n+2} h ₁ X _{n+1} + h ₂ X _n + h ₃ X _{n-1} + h ₄ X _{n-2}	X _{n+3} h ₁ X _{n+2} + h ₂ X _{n+1} + h ₃ X _n + h ₄ X _{n-1}	X _{n+4} h ₁ X _{n+3} + h ₂ X _{n+2} + h ₃ X _{n+1} + h ₄ X _n	X _{n+5} h ₁ X _{n+4} + h ₂ X _{n+3} + h ₃ X _{n+2} + h ₄ X _{n+1}	X _{n+6} h ₁ X _{n+5} + h ₂ X _{n+4} + h ₃ X _{n+3} + h ₄ X _{n+2}	X _{n+7} h ₁ X _{n+6} + h ₂ X _{n+5} + h ₃ X _{n+4} + h ₄ X _{n+3}
A0 Register Sum 0		X _n	X _{n+1} h ₀ X _n + h ₁ X _{n-1} + h ₂ X _{n-2} + h ₃ X _{n-3} + h ₄ X _{n-4}	X _{n+2} h ₀ X _{n+1} + h ₁ X _n + h ₂ X _{n-1} + h ₃ X _{n-2} + h ₄ X _{n-3}	X _{n+3} h ₀ X _{n+2} + h ₁ X _{n+1} + h ₂ X _n + h ₃ X _{n-1} + h ₄ X _{n-2}	X _{n+4} h ₀ X _{n+3} + h ₁ X _{n+2} + h ₂ X _{n+1} + h ₃ X _n + h ₄ X _{n-1}	X _{n+5} h ₀ X _{n+4} + h ₁ X _{n+3} + h ₂ X _{n+2} + h ₃ X _{n+1} + h ₄ X _n	X _{n+6} h ₀ X _{n+5} + h ₁ X _{n+4} + h ₂ X _{n+3} + h ₃ X _{n+2} + h ₄ X _{n+1}	X _{n+7} h ₀ X _{n+6} + h ₁ X _{n+5} + h ₂ X _{n+4} + h ₃ X _{n+3} + h ₄ X _{n+2}



12-bit Cascadable Multiplier-Summer
MAXIMUM RATINGS *Above which useful life may be impaired (Notes 1, 2, 3, 8)*

Storage temperature	-65°C to +150°C
Operating ambient temperature	-55°C to +125°C
V _{CC} supply voltage with respect to ground	-0.5 V to +7.0 V
Input signal with respect to ground	-3.0 V to +7.0 V
Signal applied to high impedance output	-3.0 V to +7.0 V
Output current into low outputs	25 mA
Latchup current	> 400 mA

OPERATING CONDITIONS *To meet specified electrical and switching characteristics*

Mode	Temperature Range (Ambient)	Supply Voltage
Active Operation, Commercial	0°C to +70°C	4.75 V ≤ V _{CC} ≤ 5.25 V
Active Operation, Military	-55°C to +125°C	4.50 V ≤ V _{CC} ≤ 5.50 V

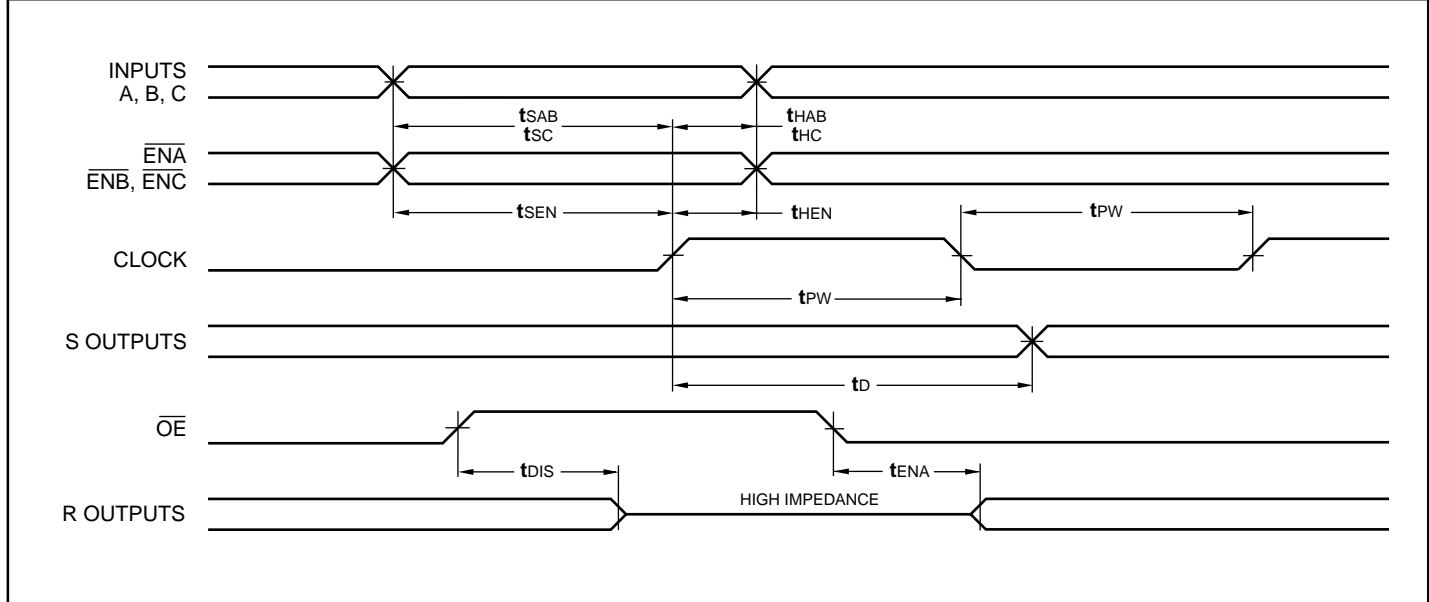
ELECTRICAL CHARACTERISTICS *Over Operating Conditions (Note 4)*

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
V _{OH}	Output High Voltage	V _{CC} = Min., I _{OH} = -2.0 mA	2.4			V
V _{OL}	Output Low Voltage	V _{CC} = Min., I _{OL} = 4.0 mA			0.5	V
V _{IH}	Input High Voltage		2.0		V _{CC}	V
V _{IL}	Input Low Voltage	(Note 3)	0.0		0.8	V
I _{Ix}	Input Current	Ground ≤ V _{IN} ≤ V _{CC} (Note 12)			±20	μA
I _{OZ}	Output Leakage Current	Ground ≤ V _{OUT} ≤ V _{CC} (Note 12)			±20	μA
I _{CC1}	V _{CC} Current, Dynamic	(Notes 5, 6)		15	25	mA
I _{CC2}	V _{CC} Current, Quiescent	(Note 7)			1.0	mA

SWITCHING CHARACTERISTICS

Symbol		Parameter		LMS12-							
				65*		50*		40		35	
				Min	Max	Min	Max	Min	Max	Min	Max
t _{CP}	Clock Period	40		35		30		25			
t _{PW}	Clock Pulse Width	15		15		12		8			
t _{SAB}	A, B, Data Setup Time	15		12		12		10			
t _{SC}	C Data Setup Time	15		10		7		7			
t _{SEN}	$\overline{EN_A}$, $\overline{EN_B}$, $\overline{EN_C}$ Setup Time	15		12		12		10			
t _{HAB}	A, B, Data Hold Time	5		5		5		2			
t _{HC}	C Data Hold Time	5		5		5		2			
t _{HEN}	$\overline{EN_A}$, $\overline{EN_B}$, $\overline{EN_C}$ Hold Time	5		5		5		2			
t _D	Clock to S-FT = 1		50		40		35		30		
	Clock to S-FT = 0		25		25		25		20		
t _{ENA}	Three-State Output Enable Delay (Note 11)		25		25		25		20		
t _{DIS}	Three-State Output Disable Delay (Note 11)		22		22		22		20		

SWITCHING WAVEFORMS

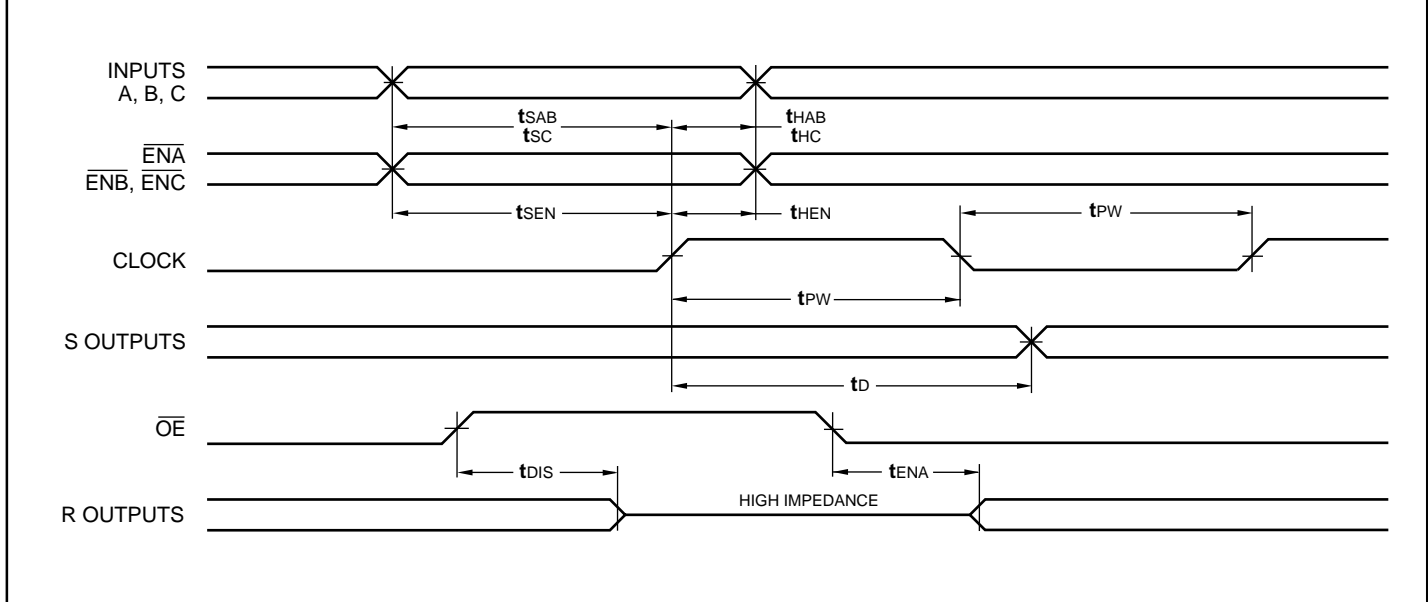


*DISCONTINUED SPEED GRADE

SWITCHING CHARACTERISTICS

Symbol		Parameter		MILITARY OPERATING RANGE (-55°C to +125°C) Notes 9, 10 (ns)					
				LMS12-					
				65*		50*		40*	
		Min	Max	Min	Max	Min	Max		
tCP	Clock Period	40		35		30			
tPW	Clock Pulse Width	15		15		12			
tSAB	A, B, Data Setup Time	15		15		12			
tSC	C Data Setup Time	15		15		12			
tSEN	\overline{ENA} , \overline{ENB} , \overline{ENC} Setup Time	15		15		12			
tHAB	A, B, Data Hold Time	5		5		5			
tHC	C Data Hold Time	5		5		5			
tHEN	\overline{ENA} , \overline{ENB} , \overline{ENC} Hold Time	5		5		5			
tD	Clock to S-FT = 1		50		45		35		
	Clock to S-FT = 0		25		25		25		
tENA	Three-State Output Enable Delay (Note 11)		25		25		25		
tDIS	Three-State Output Disable Delay (Note 11)		22		22		22		

SWITCHING WAVEFORMS



*DISCONTINUED SPEED GRADE

NOTES

1. Maximum Ratings indicate stress specifications only. Functional operation of these products at values beyond those indicated in the Operating Conditions table is not implied. Exposure to maximum rating conditions for extended periods may affect reliability.

2. The products described by this specification include internal circuitry designed to protect the chip from damaging substrate injection currents and accumulations of static charge. Nevertheless, conventional precautions should be observed during storage, handling, and use of these circuits in order to avoid exposure to excessive electrical stress values.

3. This device provides hard clamping of transient undershoot and overshoot. Input levels below ground or above VCC will be clamped beginning at -0.6 V and VCC + 0.6 V. The device can withstand indefinite operation with inputs in the range of -0.5 V to +7.0 V. Device operation will not be adversely affected, however, input current levels will be well in excess of 100 mA.

4. Actual test conditions may vary from those designated but operation is guaranteed as specified.

5. Supply current for a given application can be accurately approximated by:

$$\frac{NCV^2F}{4}$$

where

- N = total number of device outputs
- C = capacitive load per output
- V = supply voltage
- F = clock frequency

6. Tested with all outputs changing every cycle and no load, at a 5 MHz clock rate.

7. Tested with all inputs within 0.1 V of VCC or Ground, no load.

8. These parameters are guaranteed but not 100% tested.

9. AC specifications are tested with input transition times less than 3 ns, output reference levels of 1.5 V (except tDIS test), and input levels of nominally 0 to 3.0 V. Output loading may be a resistive divider which provides for specified IOH and IOL at an output voltage of VOH min and VOL max respectively. Alternatively, a diode bridge with upper and lower current sources of IOH and IOL respectively, and a balancing voltage of 1.5 V may be used. Parasitic capacitance is 30 pF minimum, and may be distributed.

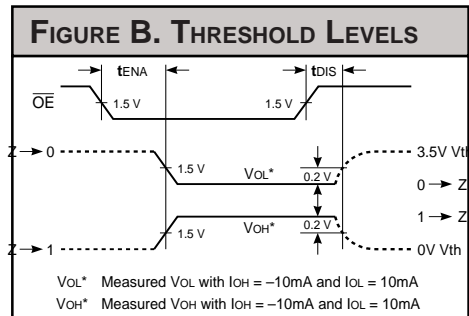
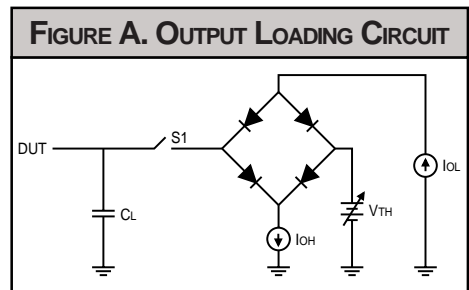
This device has high-speed outputs capable of large instantaneous current pulses and fast turn-on/turn-off times. As a result, care must be exercised in the testing of this device. The following measures are recommended:

- a. A 0.1 μF ceramic capacitor should be installed between VCC and Ground leads as close to the Device Under Test (DUT) as possible. Similar capacitors should be installed between device VCC and the tester common, and device ground and tester common.
- b. Ground and VCC supply planes must be brought directly to the DUT socket or contactor fingers.
- c. Input voltages should be adjusted to compensate for inductive ground and VCC noise to maintain required DUT input levels relative to the DUT ground pin.

10. Each parameter is shown as a minimum or maximum value. Input requirements are specified from the point of view of the external system driving the chip. Setup time, for example, is specified as a minimum since the external system must supply at least that much time to meet the worst-case requirements of all parts. Responses from the internal circuitry are specified from the point of view of the device. Output delay, for example, is specified as a maximum since worst-case operation of any device always provides data within that time.

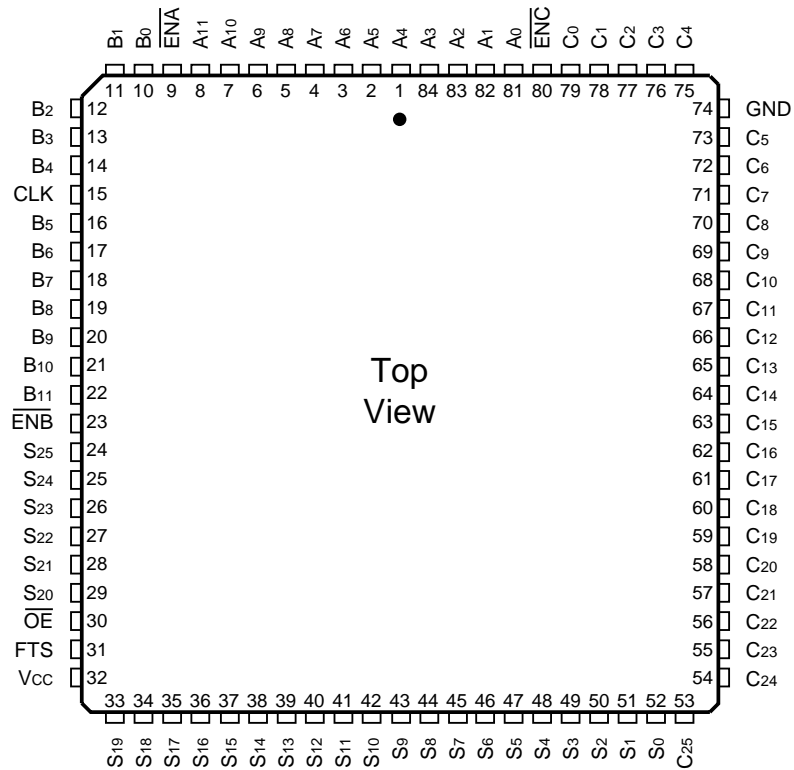
11. For the tENA test, the transition is measured to the 1.5 V crossing point with datasheet loads. For the tDIS test, the transition is measured to the ±200mV level from the measured steady-state output voltage with ±10mA loads. The balancing voltage, VTH, is set at 3.5 V for Z-to-0 and 0-to-Z tests, and set at 0 V for Z-to-1 and 1-to-Z tests.

12. These parameters are only tested at the high temperature extreme, which is the worst case for leakage current.



ORDERING INFORMATION

84-pin

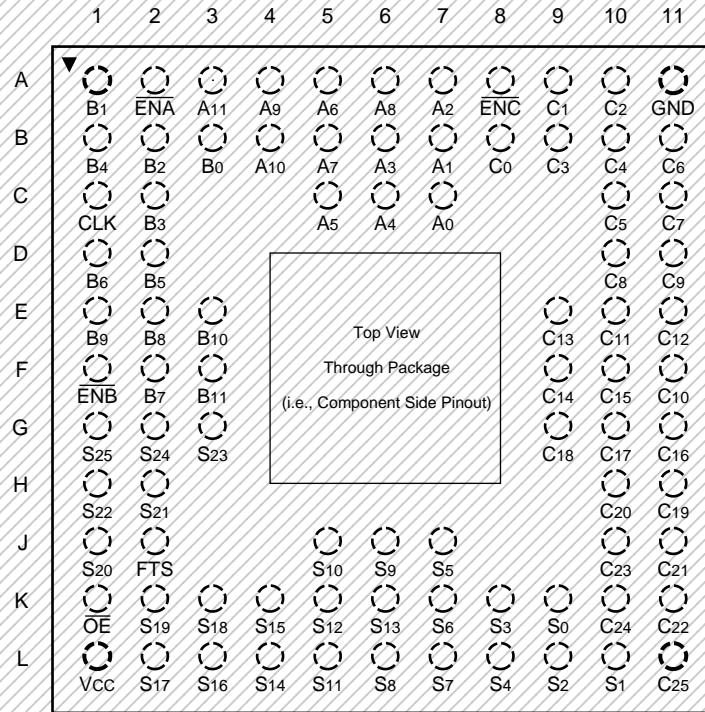


Top View

Speed	Plastic J-Lead Chip Carrier (J3)	
	0°C to +70°C — COMMERCIAL SCREENING	
40 ns		LMS12JC40
35 ns		LMS12JC35

ORDERING INFORMATION

84-pin



Discontinued Package

Speed	Ceramic Pin Grid Array (G3)
	0°C to +70°C — COMMERCIAL SCREENING
	-55°C to +125°C — COMMERCIAL SCREENING
	-55°C to +125°C — MIL-STD-883 COMPLIANT